



# 18th International Zurich Symposium on Electromagnetic Compatibility

## WS-3 on Friday September 28

Title workshop	Measurements for Signal Integrity
Organizer's name	Vittorio Ricchiuti and Flavio Maggioni
Organizer's affiliation	TechnoLabs, L'Aquila, Italy

### **Time domain and frequency domain measurements for Signal Integrity** by Vittorio Ricchiuti, Technolabs, Italy

**Abstract:** The Signal Integrity measurements consist of frequency and time domain measurements. These kinds of measurements use Time Domain Reflectometers and Vector network Analyzers. The contribution highlights how these instruments work.

### **Biased Time Domain Reflectometry measurements and modeling of active components** by Flavio Maggioni, Siemens, Italy

**Abstract:** Input clamping diodes and output buffers dynamic behaviors are important for signal integrity simulations. The presentation introduces a measurement and modeling methodology of I/O cells based on TDR measurements in biased conditions

### **Jitter: Basics, Relevance and Measurement Methods** by David Pommerenke, University of Missouri, Rolla, USA

## **Schedule Friday September 28**

13:30-14:00 Vittorio Ricchiuti, Measurements in Time Domain

14:00-14:30 Vittorio Ricchiuti, Measurements in Frequency Domain

14:30-14:45 Vittorio Ricchiuti, Eye Diagram Measurements

14:45-15:15 Flavio Maggioni, Biased Time Domain Reflectometry measurements and modeling of active components

15:15-15:30 Coffee Break

15:30-16:15 David Pommerenke, Jitter Basics: Relevance and Measurement Methods